

X-MET5100 – Light Years Ahead!

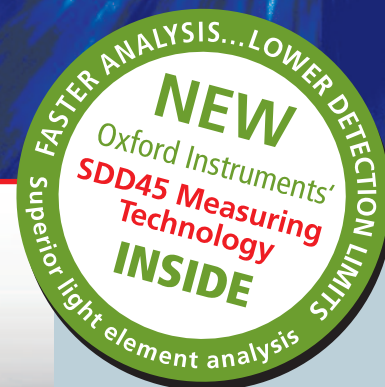
Light Element measurement now possible in a revolutionary new hand-held XRF Analyzer

X-MET5100 for Metal and Alloy Analysis QC • PMI • Scrap Sorting • FAC • RoHS

Oxford Instruments new **X-MET5100** takes the analytical performance of hand-held XRF to a completely new level.

X-MET5100 combines Oxford Instruments ground-breaking Silicon Drift Detector (SDD) with a powerful 45kV X-ray tube.

This cutting edge technology delivers fast, highly accurate measurement and the lowest limits of detection, enabling the analysis of Light Elements such as Mg, Al and Si without the need for complex vacuum or helium attachments. A truly huge step forward for hand-held X-ray fluorescence analysis.



Key Features:

- Revolutionary Light Element analysis, no awkward vacuum pumps or helium bottles
- Substantially faster analysis and throughput
- Low detection limits: ppm level analysis in 10 seconds
- Totally non-destructive testing
- Traceable Empirical Calibration to certified reference materials
- Fast and reliable identification of wide range of grades
- Withstand temperatures up to 400°C / 750°F
- Analyze weld beams down to 2 mm with optional weld beam collimator

Battery lasts for one working day!

Certified IP54 (NEMA 3) splash and dust proof!



Worldwide Technology Leader



The Business of Science®

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Light Element measurement without vacuum or helium

The **X-MET5100** is a truly rugged handheld XRF Light Element analyzer. It provides fast, highly accurate laboratory quality chemical analysis of Aluminum and Titanium alloys and can reliably analyze light elements such as silicon and phosphorus from copper, nickel and steel alloys.

With its combined proprietary SDD and X-ray technology, the **X-MET5100** dispenses with previously needed helium tanks or vacuum pump attachments.

Powerful Light Element capability combined with the non-destructive nature of the XRF technique makes **X-MET5100** an invaluable tool for the aerospace industry where often finished or sensitive samples need to be analyzed.

For the scrap recycling industry the efficient Light Element capability provides added confidence to accurately analyze nickel or copper content and enables more accurate aluminum grade identification.

Unparalleled speed, accuracy and productivity

The new **X-MET5100** is substantially faster and delivers improved precision above our field proven **X-MET5000**.

With traceable empirical calibration the **X-MET5100** ensures unparalleled measurement accuracy and speed for high throughput and real-time results you can trust. PMI inspectors and scrap sorters finally have the highly productive mobile testing tool they have been waiting for.

X-MET5100 elemental detection limits enable ppm level analysis in just 10 seconds. This level of performance improves productivity and opens up new applications for handheld analysis. **X-MET5100** can rapidly perform challenging trace element analysis such as FAC inspection in the nuclear power industry and QC of microalloyed steels used in the automotive industry.

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